

RoHS Compliant Product  
A suffix of "-C" specifies halogen & lead-free

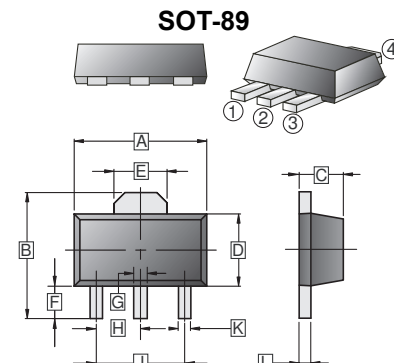
## DESCRIPTION

The SGM1K35N20 is the highest performance trench dual N-ch MOSFETs with extreme high cell density, which provide excellent  $R_{DS(ON)}$  and gate charge for most of the synchronous buck converter applications . The SGM1K35N20 meet the RoHS and Green Product requirement with full function reliability approved.

## FEATURES

- Advanced High Cell Density Trench Technology
- Super Low Gate Charge
- Green Device Available

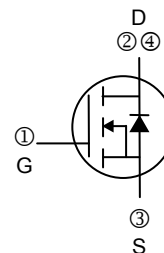
## MARKING



REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	4.40	4.60	G	0.40	0.58
B	3.94	4.25	H	1.50 TYP	
C	1.40	1.60	J	3.00 TYP	
D	2.25	2.60	K	0.32	0.52
E	1.55 TYP.		L	0.35	0.44
F	0.89	1.20			

## PACKAGE INFORMATION

Package	MPQ	Leader Size
SOT-89	1K	7 inch



## ABSOLUTE MAXIMUM RATINGS ( $T_A=25^{\circ}\text{C}$ unless otherwise specified)

Parameter	Symbol	Rating	Unit	
Drain-Source Voltage	$V_{DS}$	200	V	
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V	
Continuous Drain Current @ $V_{GS}=10\text{V}$ <sup>1</sup>	$I_D$	$T_A=25^{\circ}\text{C}$	1.6	A
		$T_A=70^{\circ}\text{C}$	1.2	A
Pulsed Drain Current <sup>4</sup>	$I_{DM}$	4	A	
Total Power Dissipation <sup>2</sup>	$P_D$	1.25	W	
Operating Junction and Storage Temperature Range	$T_J, T_{STG}$	-55~150	$^{\circ}\text{C}$	
<b>Thermal Resistance Rating</b>				
Maximum Thermal Resistance from Junction to Ambient <sup>1</sup>	$R_{\theta JA}$	36	$^{\circ}\text{C} / \text{W}$	
Maximum Thermal Resistance from Junction to Ambient <sup>2</sup>		100		
Maximum Thermal Resistance from Junction to Ambient <sup>3</sup>		250		

**ELECTRICAL CHARACTERISTICS** ( $T_J=25^\circ\text{C}$  unless otherwise specified)

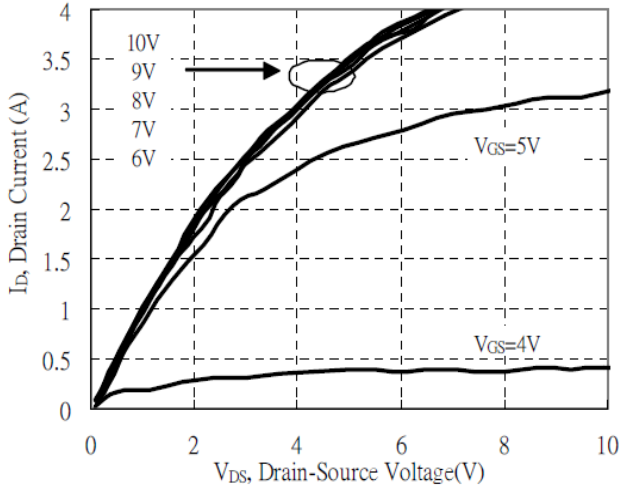
Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Condition
Drain-Source Breakdown Voltage	$BV_{DSS}$	200	-	-	V	$V_{GS}=0, I_D=250\mu\text{A}$
Gate Threshold Voltage	$V_{GS(th)}$	2	-	4	V	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$
Forward Transfer conductance	$g_{fs}$	-	1.9	-	S	$V_{DS}=5\text{V}, I_D=0.5\text{A}$
Gate-Source Leakage Current	$I_{GSS}$	-	-	$\pm 100$	nA	$V_{GS}=\pm 20\text{V}$
Drain-Source Leakage Current	$I_{DSS}$	-	-	1	$\mu\text{A}$	$V_{DS}=160\text{V}, V_{GS}=0$
Static Drain-Source On-Resistance <sup>5</sup>	$R_{DS(ON)}$	-	-	1.35	$\Omega$	$V_{GS}=10\text{V}, I_D=1\text{A}$
Total Gate Charge	$Q_g$	-	5.8	-	nC	$I_D=1\text{A}$ $V_{DS}=160\text{V}$ $V_{GS}=10\text{V}$
Gate-Source Charge	$Q_{gs}$	-	0.7	-		
Gate-Drain ("Miller") Charge	$Q_{gd}$	-	2.5	-		
Turn-On Delay Time	$T_{d(on)}$	-	33	-	nS	$V_{DD}=100\text{V}$ $I_D=1\text{A}$ $V_{GS}=10\text{V}$ $R_G=25\Omega$
Rise Time	$T_r$	-	50	-		
Turn-Off Delay Time	$T_{d(off)}$	-	150	-		
Fall Time	$T_f$	-	75	-		
Input Capacitance	$C_{iss}$	-	137	-	pF	$V_{GS}=0$ $V_{DS}=25\text{V}$ $f=1\text{MHz}$
Output Capacitance	$C_{oss}$	-	15	-		
Reverse Transfer Capacitance	$C_{rss}$	-	6	-		
<b>Source-Drain Diode</b>						
Continuous Source Current <sup>1</sup>	$I_S$	-	-	1.6	A	
Pulsed Source Current <sup>4</sup>	$I_{SM}$	-	-	4		
Forward On Voltage <sup>5</sup>	$V_{SD}$	-	-	1.2	V	$I_S=1\text{A}, V_{GS}=0\text{V}$
Reverse Recovery Time	$t_{rr}$	-	90	-	nS	$I_F=1\text{A}, di/dt=100\text{A}/\mu\text{s}$ ,
Reverse Recovery Charge	$Q_{rr}$	-	280	-	nC	$T_J=25^\circ\text{C}$

Notes:

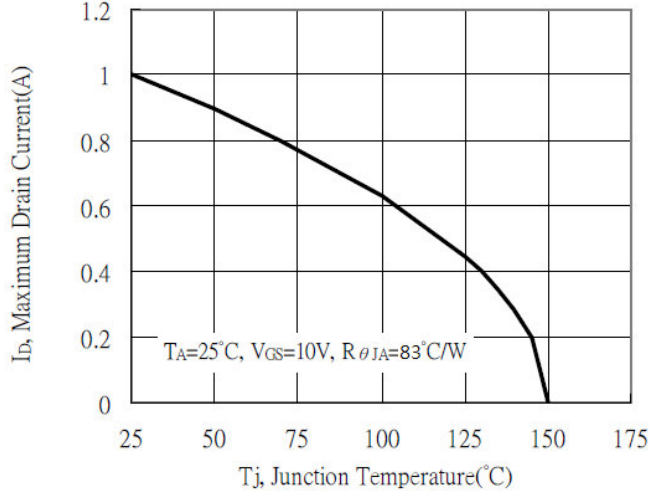
1. Surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.,  $t \leq 5\text{sec}$
2. Surface mount on Min. copper pad of FR4 board.,  $t \leq 10\text{sec}$
3. Surface mount on Min. copper pad of FR4 board.
4. Pulse width limited by maximum junction temperature.
5. Pulse test :Pulse width  $\leq 300\mu\text{s}$  , Duty cycle  $\leq 2\%$

**TYPICAL CHARACTERISTIC CURVES**

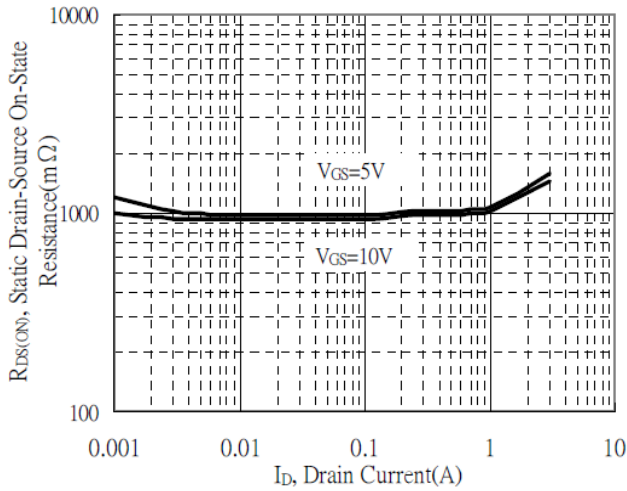
Typical Output Characteristics



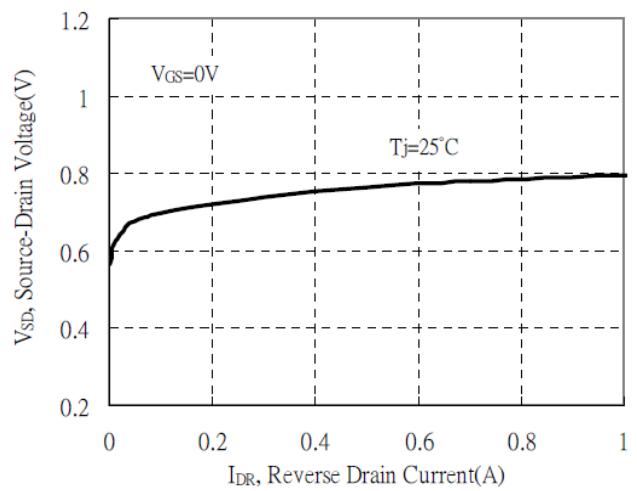
Maximum Drain Current vs Junction Temperature



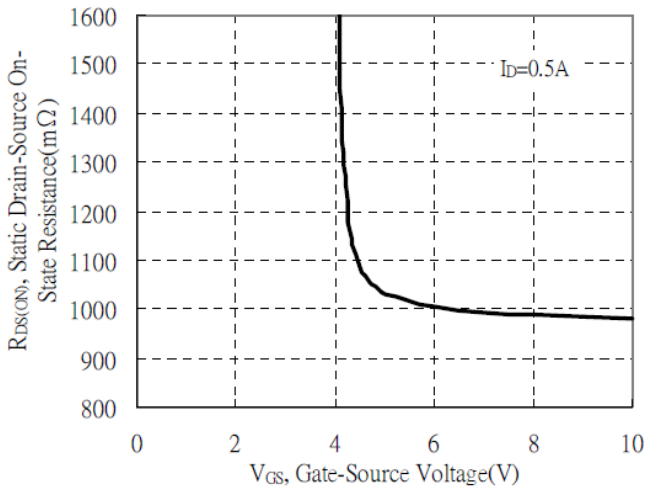
Static Drain-Source On-State resistance vs Drain Current



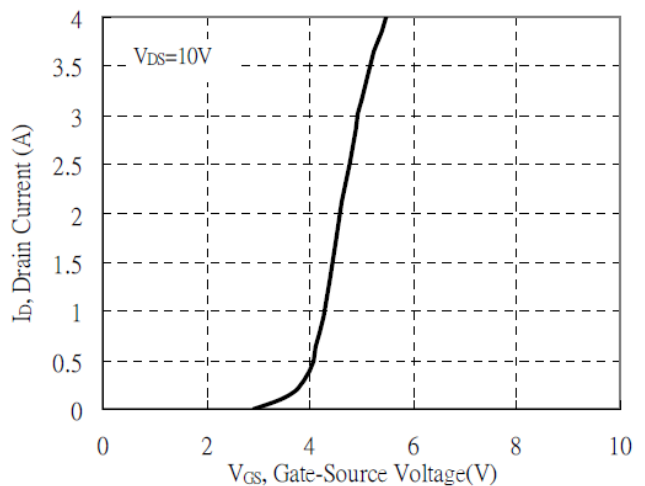
Reverse Drain Current vs Source-Drain Voltage



Static Drain-Source On-State Resistance vs Gate-Source Voltage



Typical Transfer Characteristics



**TYPICAL CHARACTERISTIC CURVES**

